



EasySegment

Deep Learning segmentation library



At a Glance

- Unsupervised mode: train only with “good” images to detect and segment anomalies and defects in new images
- Works with any image resolution
- Supports data augmentation and masks
- Compatible with CPU and GPU processing
- Includes the free Deep Learning Studio application for dataset creation, training and evaluation
- Only available as part of the Deep Learning Bundle

Benefits

What Is Deep Learning ?

Neural Networks are computing systems inspired by the biological neural networks that constitute the human brain. Convolutional Neural Networks (CNN) are a class of deep, feed-forward artificial neural networks, most commonly applied to analyzing images.

Deep Learning uses large CNNs to solve complex problems difficult or impossible to solve with so-called conventional computer vision algorithms. Deep Learning algorithms may be easier to use as they typically learn by example. They do not require the user to figure out how to classify or inspect parts. Instead, in an initial training phase, they learn just by being shown many images of the parts to be inspected. After successful training, they can be used to classify parts, or detect and segment defects.

EasySegment Description

EasySegment is the segmentation tool of Deep Learning Bundle.

EasySegment performs defect detection and segmentation. It identifies parts that contain defects, and precisely pinpoints where they are in the image.

When using its unsupervised mode, EasySegment works by learning a model of what is a “good” sample (i.e. a sample without any defect). This is done by training it only with images of “good” samples. Then, the tool can be used to classify new images as good or defective and segment the defects from these images.

By training only with images of good samples, the unsupervised mode of EasySegment is able to perform inspection even when the type of defect is not known beforehand or when defective samples are not readily available.

What is EasySegment good for?

Deep Learning is generally not suitable for applications requiring precise measurement or gauging. It is also not recommended when some types of errors (such as false negative) are completely unacceptable.

The unsupervised mode of EasySegment is good for defect detection and segmentation tasks, especially when defectives samples are hard to come by.

Deep Learning tools usually work very well with images of natural or manufactured objects that have complex surface patterns (e.g. wood, fabric, ...) that make the detection of defects by conventional machine vision algorithm very hard. Besides, the "learn by example" paradigm of Deep Learning can also reduce the development time of a computer vision process.

Data Augmentation

Deep Learning works by training a neural network, teaching it how to classify a set of reference images. The performance of the process highly depends on how representative and extensive the set of reference images is. Deep Learning Bundle implements "data augmentation", which creates additional reference images by modifying (for example by shifting, rotating, scaling) existing reference images within programmable limits. This allows Deep Learning Bundle to work with as few as one hundred training images per class.

Why Choose Open eVision's Deep Learning Bundle?

- Deep Learning Bundle has been tailored, parametrized and optimized for analyzing images, particularly for machine vision applications.
- Deep Learning Bundle has a simple API and the user can benefit from the power of deep learning technologies with only a few lines of code.
- Try before you buy: Deep Learning Bundle comes with the free Deep Learning Studio training and evaluation application.

EasyClassify and EasySegment cannot be purchased separately. They are only available as part of the Deep Learning Bundle.

Download and evaluate Deep Learning Bundle using Deep Learning Studio today, and feel free to call Euresys' support should you have any question.

Deep Learning Studio

Open eVision includes the free Deep Learning Studio application. This application assists the user during the creation of the dataset as well as the training and testing of the deep learning tool.

For the unsupervised mode of EasySegment, Deep Learning Studio allows to graphically configure the tool to fit performance requirements. For example, after training, one can choose a tradeoff between a better defect detection rate or a better good detection rate.

Performance

Deep Learning generally requires significant amounts of processing power, especially during the learning phase. Deep Learning Bundle supports standard CPUs and automatically detects Nvidia CUDA-compatible GPUs in the PC. Using a single GPU typically accelerates the learning and the processing phases by a factor of 100.

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Applications

Machine Vision for the Electronic Manufacturing Industry

- Mark inspection
- LED inspection

Machine Vision for the General Manufacturing Industries

- Presence / Absence check
- Surface analysis
- Assembly inspection
- Code quality verification for label printing machines

Machine Vision for the Food Inspection Industry

- Food inspection and sorting

Specifications

Software

Host PC Operating System	<ul style="list-style-type: none">• Windows 10 (64-bits)• Windows 8 (64-bits)• Windows 7 (64-bits)
APIs	<ul style="list-style-type: none">• Supported Integrated Development Environments and Programming Languages:<ul style="list-style-type: none">– Microsoft Visual Studio 2008® SP1 (C++, C#, VB .NET, C++/CLI)– Microsoft Visual Studio 2010® (C++, C#, VB .NET, C++/CLI)– Microsoft Visual Studio 2012® (C++, C#, VB .NET, C++/CLI)– Microsoft Visual Studio 2013® (C++, C#, VB .NET, C++/CLI)– Microsoft Visual Studio 2015® (C++, C#, VB .NET, C++/CLI)– Microsoft Visual Studio 2017® (C++, C#, VB .NET, C++/CLI)

Ordering Information

Product code - Description	<ul style="list-style-type: none">• 4188 - Open EasySegment for USB dongle• 4238 - Open EasySegment for PAR dongle• 4288 - Open EasySegment for soft-based licensing
Optional accessories	<ul style="list-style-type: none">• 6512 - eVision/Open eVision USB Dongle (empty)• 6513 - eVision/Open eVision Parallel Dongle (empty)



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